



Subclass	Class	ISSUE CLASSIFICATION

PATENT NUMBER

U.S. UTILITY Patent Application

JC-3
JC-90

SCANNED	O.I.P.E.	PATENT DATE
M H		04/11

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/6811186	D	378	58	2876-2882	Kao

APPLICANTS

Gerd Schneider
Bastian Niemann
Dirk Hambach

Method for examining structures on a semiconductor substrate

PTO-2040
12/99

ISSUING CLASSIFICATION					
ORIGINAL		CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)		
INTERNATIONAL CLASSIFICATION					
□ Continued on Issue Slip Inside File Jacket					

TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.	(Assistant Examiner) _____ (Date) _____			NOTICE OF ALLOWANCE MAILED	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____	(Primary Examiner) _____ (Date) _____			ISSUE FEE	
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	(Legal Instruments Examiner) _____ (Date) _____			Amount Due	Date Paid
ISSUE BATCH NUMBER					

WARNING:

The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368.
Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

Form PTO-436A
(Rev. 6/99)FILED WITH: DISK (CRF) FICHE CD-ROM
(Attached in pocket on right inside flap)